

<b>Notice of References Cited</b>	Application/Control No. 10/027,764	Applicant(s)/Patent Under Reexamination LOOK, THOMAS F.	
	Examiner EDWYN LABAZE	Art Unit 2876	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-5,621,571	04-1997	Bantli et al.	359/529
	B	US-6,107,920	08-2000	Eberhardt et al.	340/572.7
	C	US-6,130,613	10-2000	Eberhardt et al.	340/572.7
	D	US-6,147,605	11-2000	Vega et al.	340/572.7
	E	US-6,252,508	06-2001	Vega et al.	340/572.1
	F	US-6,317,149	11-2001	Mochida et al.	347/173
	G	US-6,384,727	05-2002	Diprizio et al.	340/572.7
	H	US-2002/0036237	03-2002	Atherton et al.	235/492
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.